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	3			Application Number	09/578,777		
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STA	TEMENT BY	APPL	ICANT	First Named Inventor	Michael L. Wach		
				Group Art Unit	3662		
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Sheet	1	of	2	Attorney Docket Number	06948.105013		

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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.





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Application Number	09/578,777			
Filing Date	May 25, 2000			
First Named Inventor	Michael L. Wach			
Group Art Unit	3662			
Examiner	Not Assigned			
Attorney Docket Number	06948.105013			

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Examiner Signature	FAMEZ -ASSAF	Date Considered	4/2/02
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LIST OF INFORMATION DISCLOSED BY APPLICANT

10 St. 10/1/2011 (Use several sheets if necessary) FILING DATE ATTY. DOCKET NO. SERIAL NO. 06948-105013 09/578,777 May 25, 2000 GROUP APPLICANT Michael L. Medin et al. U.S. PATENT DOCUMENTS SUBCLASS DOCUMENT NUMBER DATE CLASS NAME FILING DATE EXAMINER IF APPROPRIATE INITIAL 06.29.99 Yoshida 5,917,623 FOREIGN PATENT DOCUMENTS TRANSLATION DOCUMENT NUMBER DATE COUNTRY NAME YES NO. AB 0 611 097 A1 -08/17/94 EP Adar et al. Takashi Yoshida 12/08/98 AC 10-327128 Japan 02/20/97 Jones et al. AD WO 97/06616 . PCT TΑ WO 99/21316 🗹 04/29/99 **PCT** Alexander et al. AE SEP 0 4 2001 10/30/85 TA Nishi Norio AF 60217315 Japan AG 63060410 03/16/88 Japan Kusaka Satoshi 12/13/86 Japan Kitachi Nishimine AH 61282803 02/Ø5/90 02034806 Japan Ishida Hidetoshi ** ΑI OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) Kahn J. M. et al., "High-Stability 1.5M External-Cavity Semiconductor Lasers for Phase-Lock Application" AJ IEEE Photonic Technology Letters, US, IEEE Inc. New York, Vol. 1, no. 7, 1 July 1989 (1989-07-01), pages 159-161, XP000053582 ISSN: 1041-1135 the whole document Clarke R. H., "Fields in Extended Cavity Lasers", IEEE Journal of Quantum Electronics, US, IEEE Inc., New AK TA York Vol. 24, No. 5, 1 May 1988 (1988-05-01), pages 833-842, XP000706012 ISSN: 0018-9197 figure 1 Bernacki B. E. et al., "Alignment-Insensitive Technique for Wideband Tuning of an Unmodified AL Semiconductor Laser" Optics Letters, US, Optical Society of America, Washington, vol. 13, no. 9, 1 TA September 1988) (1988-09-01), pages 725-727 XP000710590 ISSN: 0146-9592 figure 1 Corzine S.W. et al., "Actively Mode-Locked Gain As P Laser With Subpicosecond Output" Appliced Physics AM Letters, American Institute of Physics. New Your, US, vol. 52 no. 5, 1 February 1988 (1988-02-01), pages TA 348-350, XP000706598, ISSN: 0003-6951, page 348, paragraph 3; figure 1 Heismann et al., "Electrooptically Tunable Narrow-Linewidth INGAASP-TI:LINB03 Extended Cavity Laser," AN Optical Fiber Communication Conference., (OFC), US, New York, IEEE, Vol. Conf. 10, 19 January 1987 74 (1987-01-19), page 149, XP000713166, ISBN: 0-936659-41-6, The whole Document. International Search Report dated 16/10/00 for International Application No. PCT/US 00/14571, for AO application entitled "Optical Feedback Assembly," filed on May 25, 2000. Partial International Search dated 19/10/00 for International Application No. PCT/US 00/14567, for AP application entitled "Method and System for Increasing the Number of Information Channels Carried by Optical Waveguides," filed on May 25, 2000. International Search Report dated 28/07/00 for International Application No. PCT/US 00/06868, for ΑQ application entitled "Optical Network Assembly," filed on March 15, 2000.

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